



**WANSEMI**  
万芯半导体

**WP047N09KF**

# **N-channel Enhancement Mode Power MOSFET**

TO-263/NMOS/90V/ $\pm 20$ V/3V/135A/4m $\Omega$

Rev0.7

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# 90V, 4.0mΩ, 135A, N-channel Enhancement Mode Power MOSFET

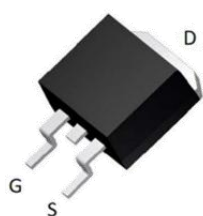
## 1.Features

- ◆ Low Gate Charge
- ◆ Ultra-low  $R_{DS(on)}$
- ◆ Halogen-free and RoHS-compliant
- ◆ 100% Avalanche&Rg Tested

$V_{DS}$	$R_{DS(on)}$ Typ.	$I_D$ Max.
90V	4.0mΩ @10V	135A

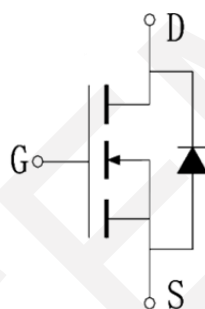
## 2.Applications

- ◆ Current Switching in DC/DC & AC/DC (SR)  
Sub-system
- ◆ Motor Driving in Power Tool, E-vehicle,  
Robotics



TO-263

Pin Description



Schematic Diagram

## 3.Package Marking and Ordering Information

Part no.	Package	Marking	Material Code	$V_{GS(th)}$	PCS/Reel	PCS/CTN.
WP047N09KF	TO-263	WP047N09	1221079000084	2.5V-2.7V	800	4000
			1221079000046	2.7V-2.9V		
			1221079000053	2.9V-3.1V		
			1221079000060	3.1V-3.3V		
			1221079000077	3.3V-3.5V		

#### 4. Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{DSS}$	90	V
Gate to Source Voltage	$V_{GSS}$	±20	V
Drain Current (DC)	$I_D$	135	A
Drain Current (Pulse), $PW \leq 300\mu s$	$I_{DP}$	336	A
Total Dissipation	$P_D$	192	W
Avalanche Energy, Single Pulsed	$E_{AS}$	552	mJ
Junction Temperature	$T_j$	150	°C
Storage Temperature	$T_{stg}$	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

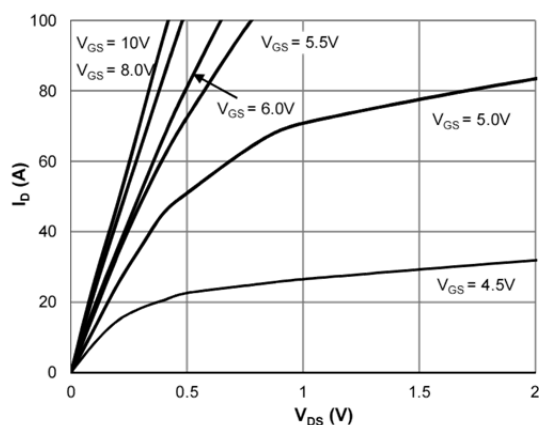
#### 5. Electrical Characteristics at Ta=25°C (Note 2)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu A$ , $V_{GS} = 0V$	90			V
Zero-Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80V$ , $V_{GS} = 0V$			1	$\mu A$
Gate to Source Leakage Current	$I_{GSS1}$	$V_{GS} = \pm 20V$ , $V_{SS} = 0V$			±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_{DS} = 250\mu A$	2.0	3.0	3.5	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 30A$ , $V_{GS} = 10V$	-	4.0	4.9	m $\Omega$
Input Capacitance	$C_{iss}$	$V_{GS} = 0V$ , $V_{DS} = 45V$ , Frequency = 1.0MHz		3525		pF
Output Capacitance	$C_{oss}$			960		pF
Reverse Transfer Capacitance	$C_{rss}$			22		pF
Turn-on Delay Time	$t_{d(on)}$	$V_{DS} = 45V$ , $R_L = 2.3\Omega$ $V_{GS} = 10V$ , $R_{GEN} = 3\Omega$		15.5		ns
Rise Time	$t_r$			29		ns
Turn-off Delay Time	$t_{d(off)}$			38		ns
Fall Time	$t_f$			24		ns
Total Gate Charge	$Q_g$	$V_{DS} = 45V$ , $V_{GS} = 10V$ , $I_D = 20A$		56		nC
	$Q_{gs}$			15.5		nC
	$Q_{gd}$			16.2		nC
Diode Forward Voltage	$V_{FSD}$	$I_S = 30A$ , $V_{GS} = 0$	0.4	0.85	1.2	V

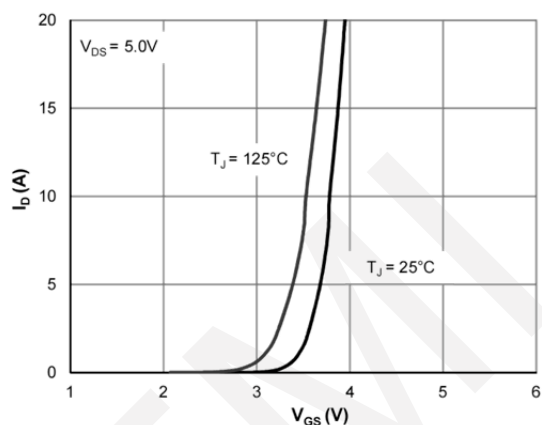
Note 2: Product parametric performance is indicated in the Electrical Characteristics for the listed test

conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

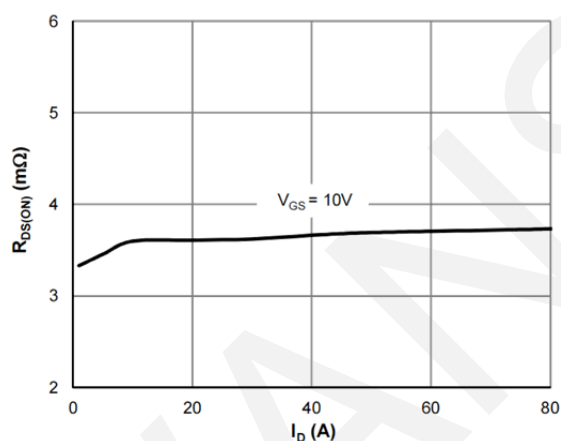
## 6. Typical electrical and thermal characteristics



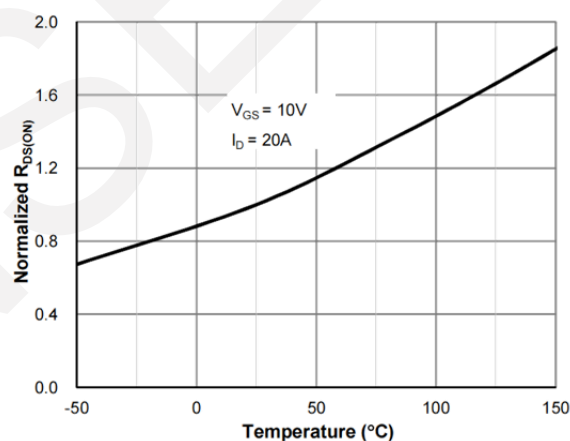
**Saturation Characteristics**



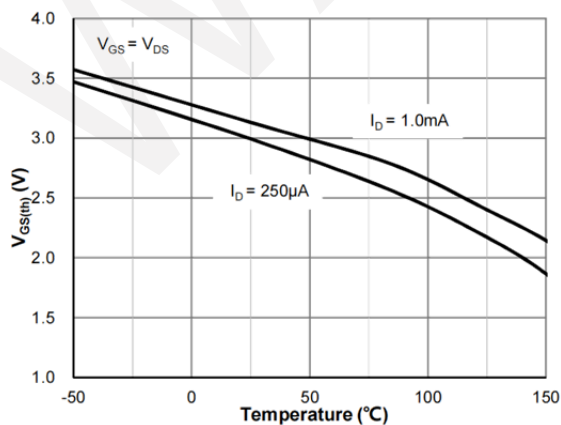
**Transfer Characteristics**



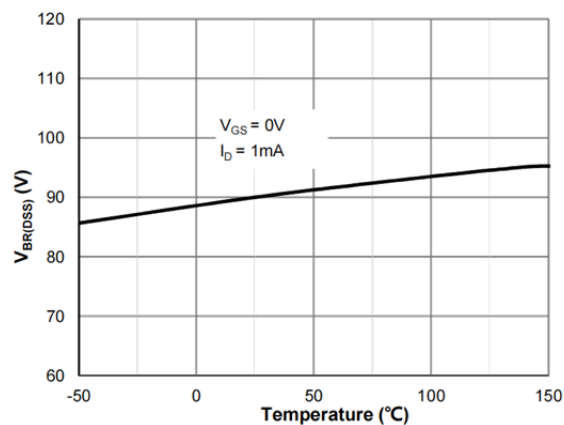
**$R_{DS(on)}$  vs. Drain Current**



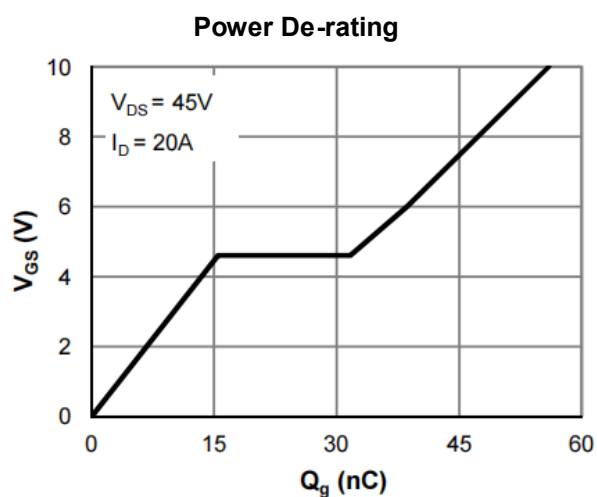
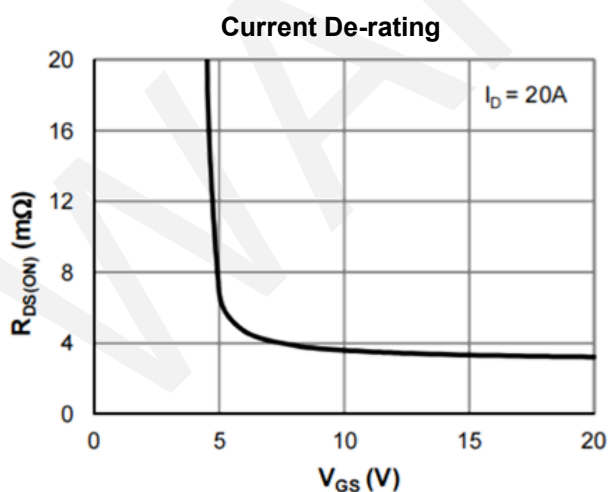
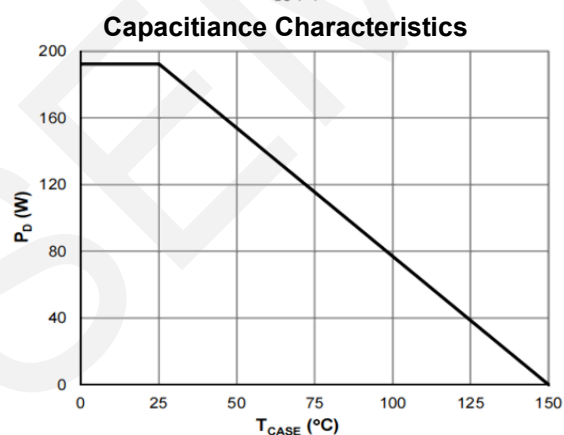
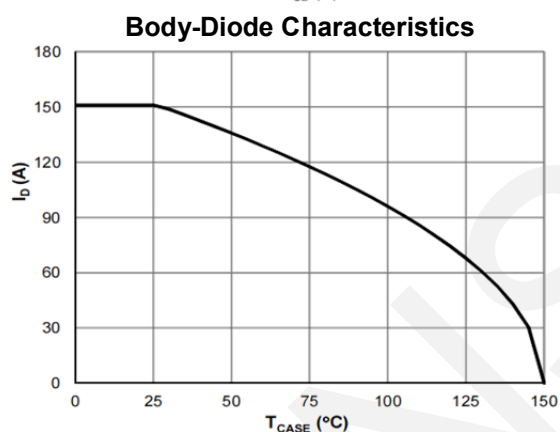
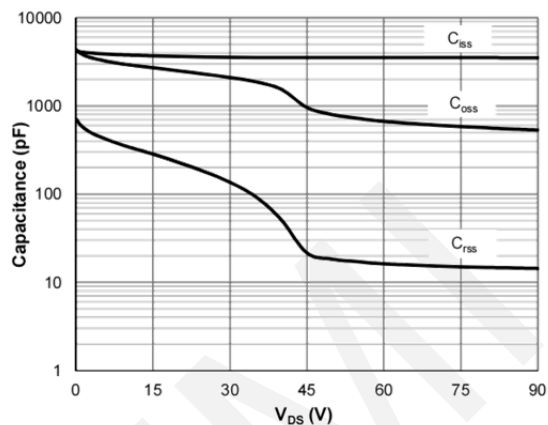
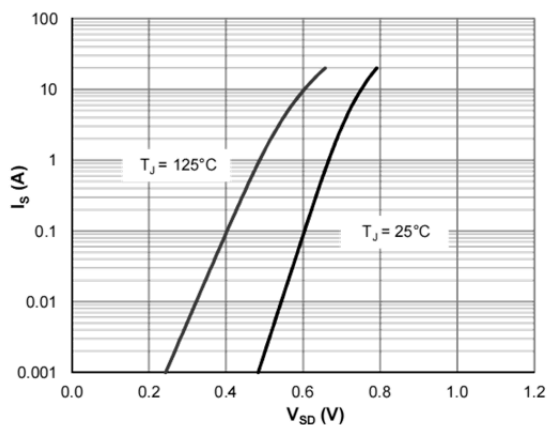
**$R_{DS(on)}$  vs. Junction Temperature**



**$V_{GS(th)}$  vs. Junction Temperature**

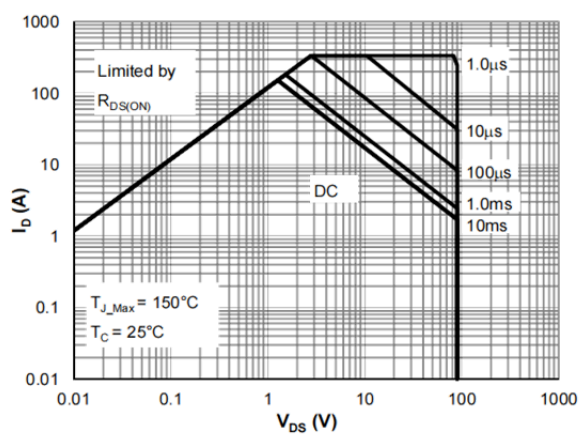


**$V_{BR(DSS)}$  vs. Junction Temperature**

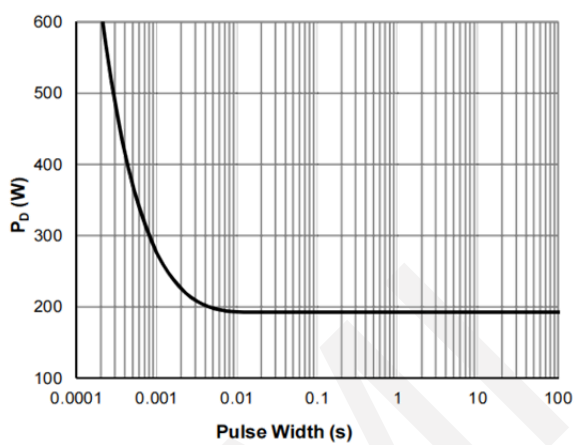


$R_{DS(on)}$  vs.  $V_{GS}$

Gate Charge

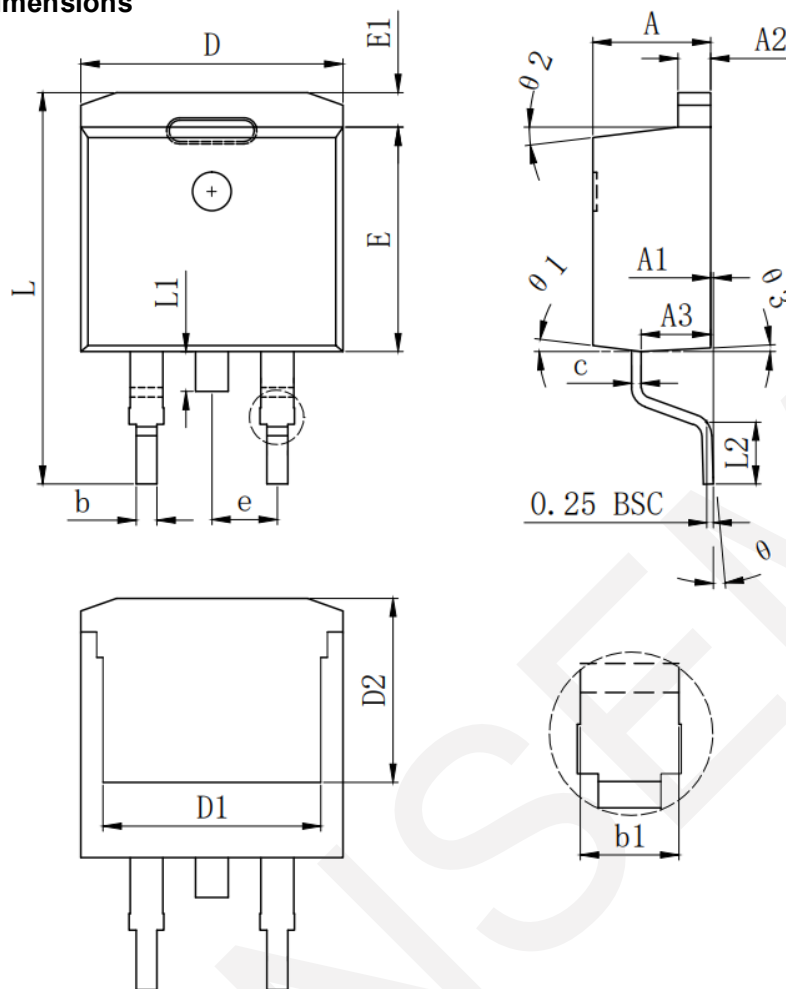


Maximum Safe Operating Area



Single Pulse Power Rating, Junction-to-Case

## 7.Package Dimensions



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	4.370	4.570	4.770
A1	0.000		0.250
A2	1.220	1.270	1.420
A3	2.490	2.690	2.890
b	0.700	0.810	0.960
b1	1.170	1.270	1.470
c	0.300	0.380	0.530
D	9.860	10.160	10.360
D1	8.400 REF		
D2	7.073 REF		
E	8.500	8.700	8.900
E1	1.070	1.270	1.470
e	2.540 TYP		
L	14.700	15.100	15.500
L1	1.400	1.550	1.700
L2	2.000	2.300	2.600
θ	0°		9°
θ 1	7° TYP		
θ 2	7° TYP		
θ 3	3° TYP		

## **8. Important Notice**

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